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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/789,312	MAD ARIF ET AL.	
Examiner	Art Unit	
Nora M. Booney	1644	

SEARCHED			
Class	Subclass	Date	Examiner
			:

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
Searched SEQ ID NO:1 and SEQ ID NO:5 including pending and commercial databases (SEE SCORE).	9/20/2007	NMR
Updated text search in STN and WEST.	9/20/2007	NMR
Updated inventor search in STN and PALM.	9/20/2007	NMR